

Notice of References Cited	Application/Control No. 10/684,445	Applicant(s)/Patent Under Reexamination BAIK, KWANG JUN	
	Examiner Christopher R. Lamb	Art Unit 2627	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-2002/0051627	05-2002	TANAKA et al.	386/96
*	C	US-6,643,085	11-2003	Shirai et al.	360/60
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	L	US-			
	M	US-			

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NON-PATENT DOCUMENTS

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